

[54] OPTICAL BEAM SCANNER

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[58] Field of Search 350/355, 356; 331/94.5 M, 94.5 K, 94.5 Q

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[57]

ABSTRACT

The optical beam scanner employs novel utilization of the well known Stark effect. By means of an external applied voltage, a change in the index of refraction of an optical medium is produced. This produces a bending effect on light transmitted through the medium. Varying the applied voltage can be used to vary the refractive index, or a refractive index gradient may be produced by providing a gradient in the applied field, to produce no moving parts scanning of the optical beam.

10 Claims, 10 Drawing Figures

